

Preface

This volume presents the proceedings of the 10th International Conference on Computer Analysis of Images and Patterns (CAIP 2003). This conference series started about 18 years ago in Berlin. Initially, the conference served as a forum for meetings between scientists from Western- and Eastern-bloc countries. Nowadays, the conference attracts participants from all over the world. The conference gives equal weight to posters and oral presentations, and the selected presentation mode is based on the most appropriate communication medium. The programme follows a single-track format, rather than parallel sessions. Non-overlapping oral and poster sessions ensure that all attendees have the opportunity to interact personally with presenters.

As for the numbers, we received a total of 160 submissions. All papers were reviewed by two to three members of the Programme Committee. The final selection was carried out by the Conference Chairs. Out of the 160 papers, 42 were selected for oral presentation and 52 as posters. At this point, we wish to thank the Programme Committee and additional referees for their timely and high-quality reviews. The paper submission and review procedure was carried out electronically. We thank Marcin Morgós from Scalar-IT Solutions for providing us with the Web-based participant registration system. We also thank the invited speakers Nicholas Ayache, John Daugman, and Dariu Gavrilă, for kindly accepting our invitation.

CAIP 2003 was organized by the Institute of Mathematics and Computing Science, University of Groningen, and took place in the University Hospital. We hope that the conference proved to be a stimulating experience, and that you had an enjoyable stay in the nice city of Groningen.

August 2003

Nicolai Petkov
Michel A. Westenberg

VIII Organization

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A. Bruhn	P. Paclik	J. Verges Llahi
J. Cech	J. Palecek	J. Vitria
C. De Stefano	D. Paulus	J. Vogel
R. Duits	P. Peer	L. Wang
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J. Goldberger	J. Ren	T. Weyrich
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